

IDS 7/25/03 1/2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2348		SERIAL NO. Unknown 10/627468	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Tyler A. Lowrey et al.		FILING DATE Filed herewith 7/25/03	
				GROUP Unknown 2812			
*Examiner Initial		Document Number	Date	U.S. PATENT DOCUMENTS			
JK	AA	6,159,818	12/00	Durcan et al.			/
JK	AB	5,953,608	09/99	Hirota			
JK	AC	6,103,568	08/00	Fujiwara			
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
JK	AD	DE 199 07 062 A 1	11/99	Germany			
JK	AE	EP 0 901 159 A2	10/99	EPO			
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JK	AF	M. Asakura et al.; "A 34ns 256Mb DRAM with Boosted Sense-Ground Scheme"; IEEE International Solid-State Circuits Conference, 1994; 2 pages					
JK	AG	T. Inaba et al.; "A 250mV Bit-Line Swing Scheme for a 1V 4Gb DRAM"; 1995 Symposium on VLSI Circuits Digest of Technical Papers; pp. 99-100					
JK	AH	Takeshi Hamamoto et al.; "Cell-Plate-Line and Bit-Line Complementarily Sensed (CBCS) Architecture for Ultra Low-Power Non-Destructive DRAMs"; 1995 Symposium on VLSI Circuits Digest of Technical Papers; pp. 79-80					
JK	AI	Mikio Asakura et al.; "Cell-Plate Line Connecting Complementary Bitline (C ²) Architecture for Battery Operating DRAMS"; LSI Research and Development Laboratory; undated; pp. 59-60					
JK	AJ	Mikio Asakura et al.; "Cell-Plate Line Connecting Complementary Bit-Line (C ²) Architecture for Battery-Operating DRAMs"; IEEE Journal of Solid-State Circuits, Vol. 27, No. 4, April 1992; pp. 597-602					
JK	AK	Satoshi Shinozaki; "DRAMs in the 21st Century"; 1996 IEDM Short Course; 5 pages					
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EXAMINER		Jennifer M. Kennedy		DATE CONSIDERED			
				November 24, 2004			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Tyler A. Lowrey et al.			
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						Yes	No	
94	AL	DE 195 43 539 C 1	04/97	Germany				
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94	AN	JP 411274434 A	10/1999	Japan (Sako)				
	AO							
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	AR							
	AS							
	AT							
EXAMINER			DATE CONSIDERED					
Gump M. Kennedy			November 24, 2004					
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10/627,468

APPLICANT
Tyler A. Lowrey et al.

FILING DATE
July 25, 2003

GROUP
2812

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							Yes	No
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	AF							

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AG		
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EXAMINER: *Quinn M. Lennoy*

DATE CONSIDERED: *November 24, 2004*

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